

Notice of References Cited	Application/Control No. 09/544,344	Applicant(s)/Patent Under Reexamination SNOW ET AL.	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
	D	US-			
	E	US-			
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	G	US-			
	H	US-			
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FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Amelina, E. A. et al, Kolloidnyi Zhurnal 1975, 37, 332-335.
	V	Creager, S. E. et al, Journal of Electroanalytical Chemistry 1994, 370, 203-211.
	W	Meldrum, F. C. et al, Journal of the Chemical Society, Faraday Transactions 1995, 91, 673-680.
	X	Leff, D. V. et al, Journal of Physical Chemistry 1995, 99, 7036-7041.

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

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	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Brust, M. et al, Advanced Materials 1995, 7, 795-797.
	V	Pehnt, M. et al, Applied Physics Letters 1995, 67, 2176-2178.
	W	Badia, A. et al, Chemistry--A European Journal 1996, 2, 359-363.
	X	Mahoney, W. J. et al, Proceedings of the Science and Technology of Atomically Engineered Materials, Richmond, Oct. 30-Nov. 4, 1995 (1996), Meeting Date 1995, 57-65. Editor(s): Jena, P. et al, Publisher: World Scientific, Singapore, Singapore.

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
 Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

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	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Schulz, D. L. et al, Conference Record of the IEEE Photovoltaic Specialists Conference 1996, 25th, 929-932.
	V	Whetten, R. L. et al, Advanced Materials 1996, 8, 428-433.
	W	Brust, M. et al, Chemical Communications 1996, 1949-1950.
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.